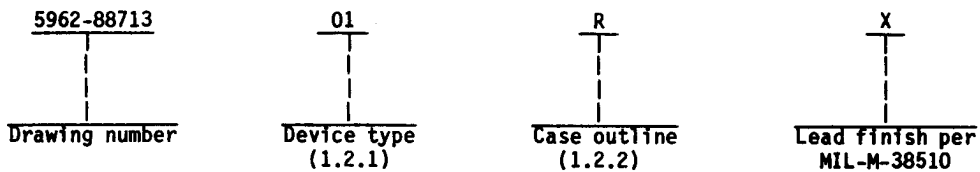




1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device types. The device types shall identify the circuit function as follows:

Device type	Generic number	Circuit function	tpd
01,05,09	C16L8	16-input 8-output AND-OR invert logic array	40,30,20 ns
02,06,10	C16R8	16-input 8-output registered AND-OR logic array	40,30,20 ns
03,07,11	C16R6	16-input 6-output registered AND-OR logic array	40,30,20 ns
04,08,12	C16R4	16-input 4-output registered AND-OR logic array	40,30,20 ns

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
R	D-8 (20-lead, 1.060" x .310" x .200"), dual-in-line package
S	F-9 (20-lead, .540" x .300" x .100"), flat package
X	C-2A (20-terminal, .358" x .358" x .075"), square chip carrier package

1.3 Absolute maximum ratings.

Supply voltage range	-0.5 V dc to +7.0 V dc
DC voltage applied to outputs in High Z	-0.5 V dc to +7.0 V dc
DC input voltage	-3.0 V dc to +7.0 V dc
Output sink current	24 mA
Thermal resistance, junction-to-case ( $\theta_{JC}$ ):	See MIL-M-38510, appendix C
Maximum power dissipation ( $P_D$ ) 1/	1.0 W
Maximum junction temperature ( $T_J$ )	+175°C
Lead temperature (soldering, 10 seconds maximum)	+260°C
Storage temperature range	-65°C to +150°C
Temperature under bias range	-55°C to +125°C

1.4 Recommended operating conditions.

Supply voltage ( $V_{CC}$ )	4.5 V dc to 5.5 V dc
High-level input voltage ( $V_{IH}$ )	2.0 V dc minimum
Low-level input voltage ( $V_{IL}$ )	0.8 V dc maximum
Case operating temperature range ( $T_C$ )	-55°C to +125°C

1/ Must withstand the added  $P_D$  due to short circuit test, e.g.,  $I_{OS}$ .

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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.2.1 Unprogrammed devices. The truth table for unprogrammed devices for contracts involving no altered item drawing shall be as specified on figure 2. When required in groups A, B, or C (see 4.3), the devices shall be programmed by the manufacturer prior to test with a minimum of 50 percent of the total number of gates programmed or to any altered item drawing pattern which includes at least 25 percent of the total number of gates programmed.

3.2.2.2 Programmed devices. The truth tables for programmed devices shall be as specified by an attached altered item drawing.

3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics shall be as specified in table I and apply over the full case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions 1/ -55°C < T <sub>C</sub> < +125°C 4.5 V < V <sub>CC</sub> < 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Output high voltage	V <sub>OH</sub>	V <sub>SS</sub> = 0 V, I <sub>OH</sub> = -2.0 mA V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	1, 2, 3	A11	2.4		V
Output low voltage	V <sub>OL</sub>	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 12.0 mA V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	1, 2, 3	A11		0.4	V
Input high voltage 2/	V <sub>IH</sub>		1, 2, 3	A11	2.0		V
Input low voltage 2/	V <sub>IL</sub>		1, 2, 3	A11		0.8	V
Input leakage current	I <sub>IX</sub>	V <sub>IN</sub> = 5.5 V to GND	1, 2, 3	A11	-10	10	μA
Output leakage current	I <sub>OZ</sub>	V <sub>CC</sub> = 5.5 V, V <sub>OUT</sub> = 5.5 V and GND	1, 2, 3	A11	-100	100	μA
Output short circuit current 3/ 4/	I <sub>OS</sub>	V <sub>CC</sub> = 5.5 V, V <sub>OUT</sub> = 0.5 V	1, 2, 3	A11		-300	mA
Power supply current 5/	I <sub>CC</sub>	V <sub>CC</sub> = 5.5 V, I <sub>OUT</sub> = 0 mA V <sub>IN</sub> = GND	1, 2, 3	A11		70	mA
Input capacitance 4/	C <sub>IN</sub>	V <sub>IN</sub> = 0 V, V <sub>CC</sub> = 5.0 V T <sub>A</sub> = 25°C, f = 1 MHz (see 4.3.1c)	4	A11		7	pF
Output capacitance 4/	C <sub>OUT</sub>	V <sub>O</sub> = 0 V, V <sub>CC</sub> = 5.0 V T <sub>A</sub> = 25°C, f = 1 MHz (see 4.3.1c)	4	A11		7	pF
Input or feedback to non-registered output	tpD	V <sub>CC</sub> = 5.5 V See figure 3 and 4	9, 10, 11	01,03,04 05,07,08 09,11,12		40 30 20	ns
Input to output enable	teA		9, 10, 11	01,03,04 05,07,08 09,11,12		40 30 20	ns
Input to output disable 4/ 6/	teR		9, 10, 11	01,03,04 05,07,08 09,11,12		40 30 20	ns
OE to output enabled	tpZX		9, 10, 11	02,03,04 06,07,08 10,11,12		25 25 20	ns
OE to output disabled 4/ 6/	tpXZ		9, 10, 11	02,03,04 06,07,08 10,11,12		25 25 20	ns

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <sup>1/</sup> V <sub>SS</sub> = 0 V, -55°C ≤ T <sub>C</sub> ≤ +125°C 4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Clock to output <sup>7/</sup>	t <sub>CO</sub>	V <sub>CC</sub> = 5.5 V See figure 3 and 4	9, 10, 11	02,03,04		25	ns
				06,07,08		20	
				10,11,12		15	
Input or feedback <sup>7/</sup> setup time	t <sub>S</sub>		9, 10, 11	02,03,04	35		ns
				06,07,08	25		
				10,11,12	20		
Hold time <sup>7/</sup>	t <sub>H</sub>		9, 10, 11	02,03,04	0		ns
		06,07,08		0			
		10,11,12		0			
Clock period <sup>4/ 7/</sup>	t <sub>p</sub>	9, 10, 11	02,03,04	60		ns	
			06,07,08	45			
			10,11,12	35			
Clock width <sup>4/ 7/</sup>	t <sub>w</sub>	9, 10, 11	02,03,04	25		ns	
			06,07,08	20			
			10,11,12	12			
<sup>4/ 7/</sup> Maximum frequency	f <sub>MAX</sub>	9, 10, 11	02,03,04	16.5		MHz	
			06,07,08	22			
			10,11,12	28.5			

- <sup>1/</sup> AC test are performed with input rise and fall times of 5 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and the output load on figure 3, configuration A.
- <sup>2/</sup> These are absolute values with respect to device ground and all overshoots due to system or tester noise are included.
- <sup>3/</sup> For test purposes, not more than one output at a time should be shorted. Short circuit test duration should not exceed one second.
- <sup>4/</sup> Tested initially and after any design or process changes that affect that parameter, and therefore shall be guaranteed to the limits specified in table I.
- <sup>5/</sup> To calculate I<sub>CC</sub> at any given operating frequency, use 70 mA + I<sub>CC</sub>(AC), where I<sub>CC</sub>(AC) = (0.6 mA/MHz) x (operating frequency in MHz).
- <sup>6/</sup> Transition is measured at steady state high level -500 mV or steady state low level +500 mV on the output from the 1.5 V level on the input and the output load on figure 3, configuration B.
- <sup>7/</sup> Test applies only to registered outputs.

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Device types	01,05,09	02,06,10	03,07,11	04,08,12
Case outlines	R,S,X	R,S,X	R,S,X	R,S,X
Terminal number	Terminal symbol			
1	I0	CP	CP	CP
2	I1	I0	I0	I0
3	I2	I1	I1	I1
4	I3	I2	I2	I2
5	I4	I3	I3	I3
6	I5	I4	I4	I4
7	I6	I5	I5	I5
8	I7	I6	I6	I6
9	I8	I7	I7	I7
10	VSS	VSS	VSS	VSS
11	I9	OE	OE	OE
12	00	00	I/00	I/00
13	I/01	01	01	I/01
14	I/02	02	02	02
15	I/03	03	03	03
16	I/04	04	04	04
17	I/05	05	05	05
18	I/06	06	06	I/06
19	07	07	I/07	I/07
20	VCC	VCC	VCC	VCC

FIGURE 1. Terminal connections.

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Device types 01, 05, and 09

Inputs										Outputs							
I <sub>9</sub>	I <sub>8</sub>	I <sub>7</sub>	I <sub>6</sub>	I <sub>5</sub>	I <sub>4</sub>	I <sub>3</sub>	I <sub>2</sub>	I <sub>1</sub>	I <sub>0</sub>	O <sub>7</sub>	I/O <sub>6</sub>	I/O <sub>5</sub>	I/O <sub>4</sub>	I/O <sub>3</sub>	I/O <sub>2</sub>	I/O <sub>1</sub>	I/O <sub>0</sub>
X	X	X	X	X	X	X	X	X	X	Z	Z	Z	Z	Z	Z	Z	Z

Device types 02, 06, and 10

Inputs										Outputs							
CP	OE	I <sub>7</sub>	I <sub>6</sub>	I <sub>5</sub>	I <sub>4</sub>	I <sub>3</sub>	I <sub>2</sub>	I <sub>1</sub>	I <sub>0</sub>	O <sub>7</sub>	O <sub>6</sub>	O <sub>5</sub>	O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>	O <sub>0</sub>
X	H	X	X	X	X	X	X	X	X	Z	Z	Z	Z	Z	Z	Z	Z
X	L	X	X	X	X	X	X	X	X	H	H	H	H	H	H	H	H

Device types 03, 07, and 11

Inputs										Outputs							
CP	OE	I <sub>7</sub>	I <sub>6</sub>	I <sub>5</sub>	I <sub>4</sub>	I <sub>3</sub>	I <sub>2</sub>	I <sub>1</sub>	I <sub>0</sub>	I/O <sub>7</sub>	I/O <sub>6</sub>	I/O <sub>5</sub>	I/O <sub>4</sub>	I/O <sub>3</sub>	I/O <sub>2</sub>	I/O <sub>1</sub>	I/O <sub>0</sub>
X	H	X	X	X	X	X	X	X	X	Z	Z	Z	Z	Z	Z	Z	Z
X	L	X	X	X	X	X	X	X	X	Z	H	H	H	H	H	H	Z

Device types 04, 08, and 12

Inputs										Outputs							
CP	OE	I <sub>7</sub>	I <sub>6</sub>	I <sub>5</sub>	I <sub>4</sub>	I <sub>3</sub>	I <sub>2</sub>	I <sub>1</sub>	I <sub>0</sub>	I/O <sub>7</sub>	I/O <sub>6</sub>	O <sub>5</sub>	O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	I/O <sub>1</sub>	I/O <sub>0</sub>
X	H	X	X	X	X	X	X	X	X	Z	Z	Z	Z	Z	Z	Z	Z
X	L	X	X	X	X	X	X	X	X	Z	Z	H	H	H	H	Z	Z

NOTES:

1. Z = Three state
2. X = Don't care

FIGURE 2. Truth table (unprogrammed).

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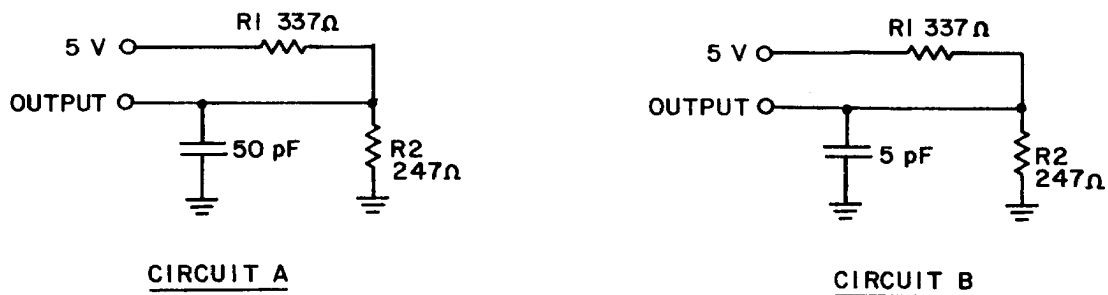


FIGURE 3. Output load circuit.

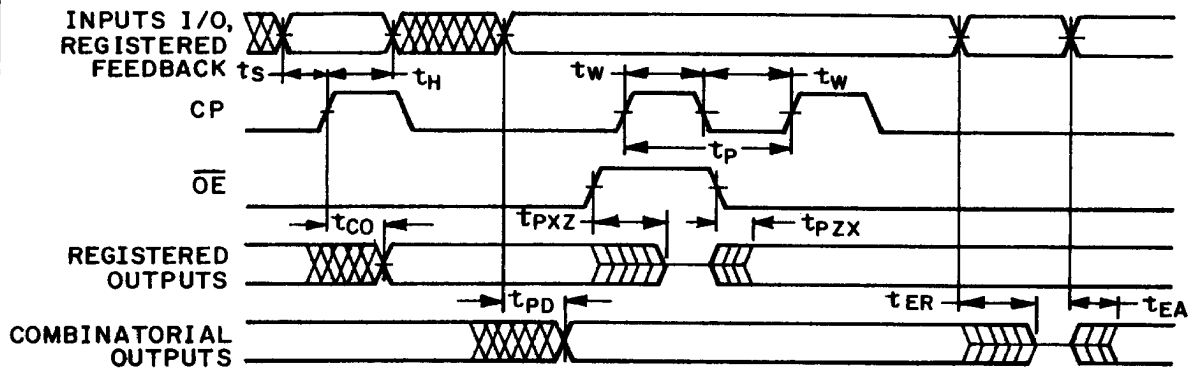


FIGURE 4. Switching waveforms.

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3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

3.9 Processing options. Since the device is capable of being programmed by either the manufacturer or the user to result in a wide variety of configurations; two processing options are provided for selection in the contract, using an altered item drawing.

3.9.1 Unprogrammed device delivered to the user. All testing shall be verified through group A testing as defined in 3.2.2.1 and table II. It is recommended that users perform subgroups 7 and 9 after programming to verify the specific program configuration.

3.9.2 Manufacturer-programmed device delivered to the user. All testing requirements and quality assurance provisions herein, including the requirements of the altered item drawing, shall be satisfied by the manufacturer prior to delivery.

#### 4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test (method 1015 of MIL-STD-883).

(1) Test condition C or D using the circuit submitted with the certificate of compliance (see 3.5 herein).

(2)  $T_A = +125^{\circ}\text{C}$ , minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

##### 4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroup 4 ( $C_{IN}$  and  $C_0$  measurement) shall be measured only for the initial test and after any design or process changes which may affect capacitance.

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- d. Unprogrammed devices shall be tested for programmability and ac performance compliance to the requirements of Group A, subgroups 9, 10, and 11.
- (1) A sample shall be selected to satisfy programmability requirements prior to performing subgroups 9, 10, and 11. Twelve devices shall be submitted to programming (see 3.2.2.1). If more than two devices fail to program, the lot shall be rejected. At the manufacturer's option, the sample may be increased to 24 total devices with no more than four total device failures allowable.
  - (2) Ten devices from the programmability sample shall be submitted to the requirements of group A, subgroups 9, 10, and 11. If more than two devices fail, the lot shall be rejected. At the manufacturer's option, the sample may be increased to 20 total devices with no more than 4 total device failures allowable.

**4.3.2 Groups C and D inspections.**

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
  - (1) Test condition C or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
  - (2)  $T_A = +125^\circ\text{C}$ , minimum.
  - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
- c. For quality conformance inspection, the programmability sample (see 4.3.1d) shall be included in subgroup 1 test.

**4.4 Programming procedures.** The programming procedures shall be as specified by the device manufacturer.

**4.5 Electrostatic discharge sensitivity (ESDS).** Electrostatic discharge sensitivity (ESDS) testing shall be performed in accordance with MIL-STD-883, method 3015 and MIL-M-38510 for initial testing and after any design or process changes which may affect input or output protection circuitry. The option to categorize devices as ESD sensitive without performing the test is not allowed. Only those device types that pass ESDS testing at 1000 volts or greater shall be considered as conforming to the requirements of this drawing.

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TABLE II. Electrical test requirements. 1/ 2/ 3/ 4/

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (pre burn-in) (method 5004)	1
Final electrical test parameters (method 5004) for unprogrammed devices	1*,2,3,7*,8
Final electrical test parameters (method 5004) for programmed devices	1*,2,3,7*,8,9
Group A test requirements (method 5005)	1,2,3,4**,7, 8,9,10,11
Groups C and D end-point electrical parameters (method 5005)	2,3,7,8

- 1/ \* indicates PDA applies to subgroups 1 and 7.  
 2/ Any or all subgroups may be combined when using high-speed testers.  
 3/ \*\* see 4.3.1c.  
 4/ Subgroups 7 and 8 shall consist of verifying the data pattern.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number 1/	Replacement military specification part number
5962-8871301RX	65786	PALC16L8-40DMB	
5962-8871301SX	65786	PALC16L8-40KMB	
5962-8871301XX	65786	PALC16L8-40LMB	
5962-8871302RX	65786	PALC16R8-40DMB	
5962-8871302SX	65786	PALC16R8-40KMB	
5962-8871302XX	65786	PALC16R8-40LMB	
5962-8871303RX	65786	PALC16R6-40DMB	
5962-8871303SX	65786	PALC16R6-40KMB	
5962-8871303XX	65786	PALC16R6-40LMB	
5962-8871304RX	65786	PALC16R4-40DMB	
5962-8871304SX	65786	PALC16R4-40KMB	
5962-8871304XX	65786	PALC16R4-40LMB	
5962-8871305RX	65786	PALC16L8-30DMB	
5962-8871305SX	65786	PALC16L8-30KMB	
5962-8871305XX	65786	PALC16L8-30LMB	
5962-8871306RX	65786	PALC16R8-30DMB	
5962-8871306SX	65786	PALC16R8-30KMB	
5962-8871306XX	65786	PALC16R8-30LMB	
5962-8871307RX	65786	PALC16R6-30DMB	
5962-8871307SX	65786	PALC16R6-30KMB	
5962-8871307XX	65786	PALC16R6-30LMB	
5962-8871308RX	65786	PALC16R4-30DMB	
5962-8871308SX	65786	PALC16R4-30KMB	
5962-8871308XX	65786	PALC16R4-30LMB	
5962-8871309RX	65786	PALC16L8-20DMB	
5962-8871309SX	65786	PALC16L8-20KMB	
5962-8871309XX	65786	PALC16L8-20LMB	
5962-8871310RX	65786	PALC16R8-20DMB	
5962-8871310SX	65786	PALC16R8-20KMB	
5962-8871310XX	65786	PALC16R8-20LMB	
5962-8871311RX	65786	PALC16R6-20DMB	
5962-8871311SX	65786	PALC16R6-20KMB	
5962-8871311XX	65786	PALC16R6-20LMB	
5962-8871312RX	65786	PALC16R4-20DMB	
5962-8871312SX	65786	PALC16R4-20KMB	
5962-8871312XX	65786	PALC16R4-20LMB	

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE  
number

65786

Vendor name  
and address

Cypress Semiconductor Corporation  
3901 North First Street  
San Jose, CA 95134

<b>STANDARDIZED MILITARY DRAWING</b> DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE <b>A</b>	5962-88713	
		REVISION LEVEL	SHEET 12

DESC FORM 193A  
SEP 87

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